

**Search Notes**

Application/Control No.

10/776,783

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

ASANO ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
252	79.1	2/9/2006	BT
252	79.4	2/9/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUB, JPO, EPO, DERWENT database	2/9/2006	BT